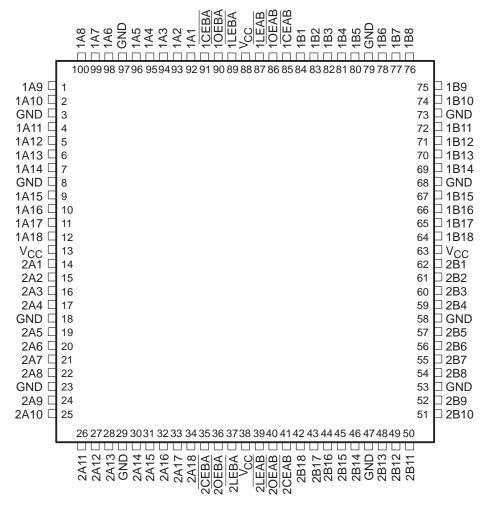
- Members of the Texas Instruments
 Widebus+™ Family
- State-of-the-Art EPIC-IIB™ BiCMOS Design Significantly Reduces Power Dissipation
- Latch-Up Performance Exceeds 500 mA Per JEDEC Standard JESD-17
- Typical V_{OLP} (Output Ground Bounce)
 < 0.8 V at V_{CC} = 5 V, T_A = 25°C
- High-Impedance State During Power Up and Power Down
- Released as DSCC SMD 5962-9557801NXD

- Distributed V_{CC} and GND Pin Configuration
 Minimizes High-Speed Switching Noise
- High-Drive Outputs (–32-mA I_{OH}, 64-mA I_{OL})
- Bus Hold on Data Inputs Eliminates the Need for External Pullup/Pulldown Resistors
- Package Options Include 100-Pin Plastic Thin Quad Flat (PZ) Package With 14 × 14-mm Body Using 0.5-mm Lead Pitch and Space-Saving 100-Pin Ceramic Quad Flat (HS) Package[†]

'ABTH32543 . . . PZ PACKAGE (TOP VIEW)



† The HS package is not production released.

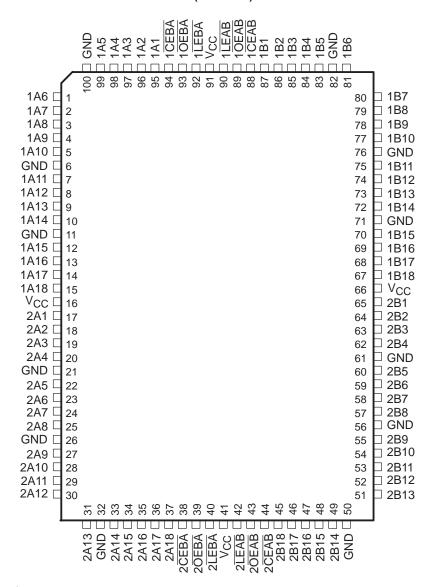


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SN54ABTH32543 . . . HS PACKAGE[†] (TOP VIEW)



† For HS package availability, please contact the factory or your local TI Field Sales Office.

description

The 'ABTH32543 are 36-bit registered transceivers that contain two sets of D-type latches for temporary storage of data flowing in either direction. These devices can be used as two 18-bit transceivers or one 36-bit transceiver. Separate latch-enable (LEAB or LEBA) and output-enable (OEAB or OEBA) inputs are provided for each register to permit independent control in either direction of data flow.

The A-to-B enable (CEAB) input must be low to enter data from A or to output data from B. If CEAB is low and LEAB is low, the A-to-B latches are transparent; a subsequent low-to-high transition of LEAB puts the A latches in the storage mode. With CEAB and OEAB both low, the 3-state B outputs are active and reflect the data present at the output of the A latches. Data flow from B to A is similar but requires using the CEBA, LEBA, and OEBA inputs.



description (continued)

When V_{CC} is between 0 and 2.1 V, the device is in the high-impedance state during power up or power down. However, to ensure the high-impedance state above 2.1 V, \overline{OE} should be tied to V_{CC} through a pullup resistor; the minimum value of the resistor is determined by the current-sinking capability of the driver.

Active bus-hold circuitry is provided to hold unused or floating data inputs at a valid logic level.

The SN54ABTH32543 is characterized for operation over the full military temperature range of –55°C to 125°C. The SN74ABTH32543 is characterized for operation from –40°C to 85°C.

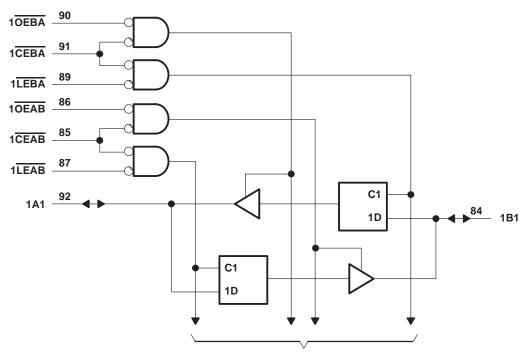
FUNCTION TABLE† (each 18-bit section)

	OUTPUT			
CEAB	LEAB	OEAB	Α	В
Н	Х	Х	Х	Z
Х	Χ	Н	Χ	Z
L	Н	L	Χ	в ₀ ‡
L	L	L	L	L
L	L	L	Н	Н

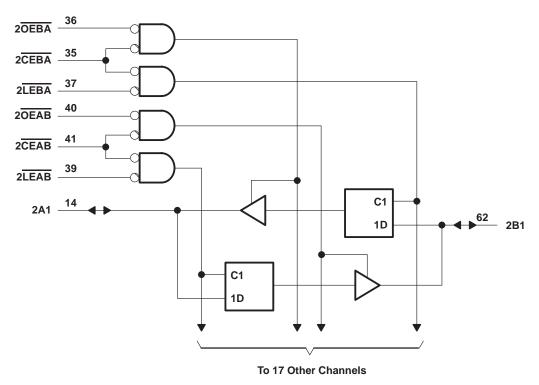
[†] A-to-B data flow is shown; B-to-A flow control is the same except that it uses CEBA, LEBA, and OEBA.

[‡]Output level before the indicated steady-state input conditions were established

logic diagram (positive logic)



To 17 Other Channels



Pin numbers shown are for the PZ package.



SN54ABTH32543, SN74ABTH32543 36-BIT REGISTERED BUS TRANSCEIVERS WITH 3-STATE OUTPUTS

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absolute maximum ratings over operating free-air temperature range (unless otherwise noted)†

Supply voltage range, V _{CC}	0.5 V to 7 V
Input voltage range, V _I (except I/O ports) (see Note 1)	0.5 V to 7 V
Voltage range applied to any output in the high or power-off state, VO	0.5 V to 5.5 V
Current into any output in the low state, IO: SN54ABTH32543	96 mA
SN74ABTH32543	128 mA
Input clamp current, I _{IK} (V _I < 0)	–18 mA
Output clamp current, I _{OK} (V _O < 0)	–50 mA
Package thermal impedance, θ _{JA} (see Note 2): PZ package	50°C/W
Storage temperature range, T _{stq}	–65°C to 150°C

[†] Stresses beyond those listed under "absolute maximum ratings" may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated under "recommended operating conditions" is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.

2. The package thermal impedance is calculated in accordance with EIA/JEDEC Std JESD51.

recommended operating conditions (see Note 3)

				H32543	SN74ABTI	UNIT	
			MIN	MAX	MIN	MAX	UNIT
VCC	Supply voltage	4.5	5.5	4.5	5.5	V	
VIH	High-level input voltage		2		2		V
V _{IL}	Low-level input voltage			0.8		0.8	V
VI	Input voltage			VCC	0	VCC	V
loh	High-level output current			-24		-32	mA
loL	Low-level output current			48		64	mA
Δt/Δν	Input transition rise or fall rate	Outputs enabled		10		10	ns/V
Δt/ΔV _{CC}	Power-up ramp rate		200		200		μs/V
TA	Operating free-air temperature		-55	125	-40	85	°C

NOTE 3: Unused control pins must be held high or low to prevent them from floating.

NOTES: 1. The input and output negative-voltage ratings may be exceeded if the input and output clamp-current ratings are observed.

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electrical characteristics over recommended operating free-air temperature range (unless otherwise noted)

PARAMETER		TEST CONDITIONS		SN54	ABTH3	2543	SN74ABTH32543			UNIT	
PAI	RAMETER	TEST CONDITIONS		MIN	TYP [†]	MAX	MIN	TYP [†]	MAX	UNII	
VIK		V _{CC} = 4.5 V,	I _I = -18 mA			-1.2			-1.2	V	
		$V_{CC} = 4.5 \text{ V},$	$I_{OH} = -3 \text{ mA}$	2.5			2.5				
l vau		$V_{CC} = 5 V$,	$I_{OH} = -3 \text{ mA}$	3			3			V	
VOH		V _{CC} = 4.5 V	$I_{OH} = -24 \text{ mA}$	2						·	
		VCC = 4.5 V	$I_{OH} = -32 \text{ mA}$				2				
VOL		V _{CC} = 4.5 V	I_{OL} = 48 mA			0.55			0.55	V	
VOL		VCC = 4.5 V	I_{OL} = 64 mA						0.55	V	
V _{hys}					100			100		mV	
	Control inputs	$V_{CC} = 0 \text{ to } 5.5 \text{ V},$	$V_I = V_{CC}$ or GND						±1	-	
	A or B ports	$V_{CC} = 2.1 \text{ V to } 5.5 \text{ V},$	$V_I = V_{CC}$ or GND						±20		
'I	Control inputs	VCC = 5.5 V,	V _I = V _{CC} or GND			±1					
	A or B ports	VCC = 5.5 v,				±20					
11/2 - 1-15	A or B ports	V _{CC} = 4.5 V	V _I = 0.8 V				100			μΑ	
l(hold)	A of B ports	VCC = 4.5 V	V _I = 2 V				-100				
lozpu [‡]		$V_{CC} = 0$ to 2.1 V, $V_{O} = 0.5$				±50			±50	μΑ	
lozpd [‡]	<u> </u>	$V_{CC} = 2.1 \text{ V to } 0, V_{O} = 0.5$				±50			±50	μΑ	
l _{off}		$V_{CC} = 0$,	V_I or $V_O \le 4.5 \text{ V}$						±100	μΑ	
ICEX		$V_{CC} = 5.5 \text{ V}, V_{O} = 5.5 \text{ V}$	Outputs high			50			50	μΑ	
I _O §		$V_{CC} = 5.5 \text{ V},$	V _O = 2.5 V	-50	-100	-180	- 50	-100	-180	mA	
			Outputs high			3			3		
Icc		$V_{CC} = 5.5 \text{ V}, I_{O} = 0,$ $V_{I} = V_{CC} \text{ or GND}$	Outputs low			20			20	mA	
		11 100 31 3112	Outputs disabled			2			2		
∆ICC¶		V_{CC} = 5.5 V, One input at 3 Other inputs at V_{CC} or GN				1			1	mA	
Ci	Control inputs	V _I = 2.5 V or 0.5 V			3.5			3.5		pF	
Cio	A or B ports	V _O = 2.5 V or 0.5 V			9.5			9.5		pF	

[†] All typical values are at $V_{CC} = 5 \text{ V}$, $T_A = 25^{\circ}\text{C}$.

timing requirements over recommended ranges of supply voltage and operating free-air temperature (unless otherwise noted) (see Figure 1)

			V _{CC} = T _A = 2	= 5 V, !5°C#	SN54ABTI	H32543	SN74ABTI	132543	UNIT
			MIN	MAX	MIN	MAX	MIN	MAX	
t _W Pulse duration, LEAB or LEBA low			3.3		3.3		3.3		ns
	Cotup time	Data before LEAB↑ or LEBA↑	2.1		2.6		2.1		ns
^t su	t _{SU} Setup time	Data before CEAB↑ or CEBA↑	1.7		2		1.7		
t _h Hold time	Hold time	Data after LEAB↑ or LEBA↑	0.6		1.1		0.6		ns
	HOIU IIIIIE	Data after CEAB↑ or CEBA↑	0.9		1.2		0.9	·	

[#]These limits apply only to the SN74ABTH32543.



[‡] This parameter is specified by characterization.

[§] Not more than one output should be tested at a time, and the duration of the test should not exceed one second.

[¶] This is the increase in supply current for each input that is at the specified TTL voltage level rather than VCC or GND.

SN54ABTH32543, SN74ABTH32543 36-BIT REGISTERED BUS TRANSCEIVERS WITH 3-STATE OUTPUTS

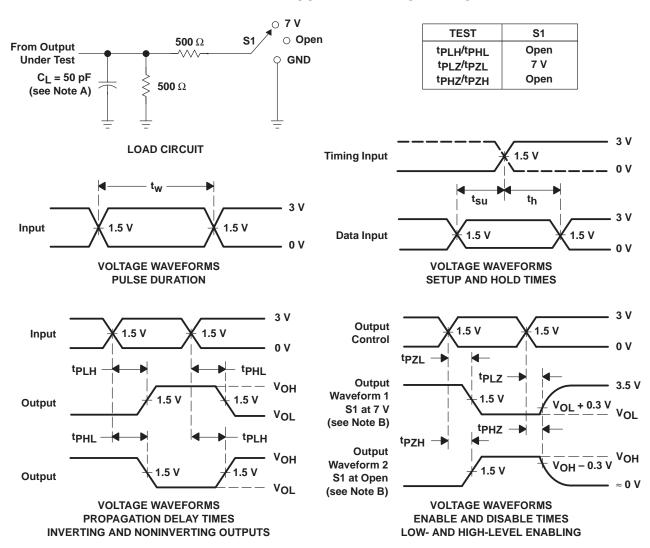
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switching characteristics over recommended ranges of supply voltage and operating free-air temperature, C_L = 50 pF (unless otherwise noted) (see Figure 1)

PARAMETER	FROM (INPUT)	TO (OUTPUT)		V _{CC} = 5 V, T _A = 25°C†		SN54ABTH32543		SN74ABTH32543		UNIT
	(INFOT)	(001F01)	MIN	TYP	MAX	MIN	MAX	MIN	MAX	
tPLH	A or B	B or A	1	3.5	5.2	0.5	6.3	1	5.9	ns
t _{PHL}	AUIB	BULA	1	3.5	5.1	0.5	5.9	1	5.7	115
t _{PLH}	LE .	A or B	1.9	4.6	6.3	0.8	7.9	1.9	7.5	ns
t _{PHL}	LE	AUIB	1.9	4.3	5.9	0.8	6.9	1.9	6.6	115
^t PZH	CE	A or B	1.7	4.3	6.7	0.8	8.3	1.7	8	ns
tPZL		AUIB	2.6	5.2	8	1	8.8	2.6	8.8	115
^t PHZ	CE	A or B	1.6	3.8	6.6	0.5	7.4	1.6	7.1	ns
t _{PLZ}	CE	AUIB	2.4	4.6	7	1	7.9	2.4	7.5	115
^t PZH	ŌĒ	A or B	1.4	3.8	6.1	0.5	7.6	1.4	7.3	no
tpzL	UE	AUID	2.3	4.7	7.4	1	8.2	2.3	8.1	ns
t _{PHZ}	ŌĒ	A or B	1.3	3.4	6.1	0.5	6.7	1.3	6.5	no
tPLZ		AUID	2	4.2	6.6	0.8	7.2	2	6.9	ns

[†] These limits apply only to the SN74ABTH32543.

PARAMETER MEASUREMENT INFORMATION



NOTES: A. C_L includes probe and jig capacitance.

- B. Waveform 1 is for an output with internal conditions such that the output is low except when disabled by the output control. Waveform 2 is for an output with internal conditions such that the output is high except when disabled by the output control.
- C. All input pulses are supplied by generators having the following characteristics: PRR \leq 10 MHz, Z_{Q} = 50 Ω , t_{f} \leq 2.5 ns, t_{f} \leq 2.5 ns.
- D. The outputs are measured one at a time with one transition per measurement.

Figure 1. Load Circuit and Voltage Waveforms



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